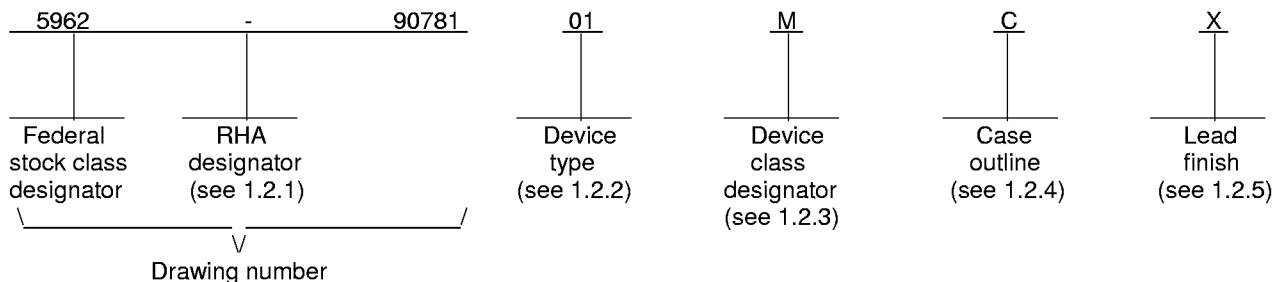


REVISIONS																	
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED														
A	Revised to use alternate die/fabrication requirements and "QD" certification mark. New boilerplate. -ljs	99-10-22	Raymond Monnin														
<p>The original first page of this drawing has been replaced.</p>																	
REV																	
SHEET																	
REV																	
SHEET																	
REV STATUS	REV	A	A	A	A	A	A	A	A	A	A	A	A	A	A		
OF SHEETS	SHEET	1	2	3	4	5	6	7	8	9	10	11	12				
PMIC N/A	PREPARED BY Donald R. Osborne	DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216															
STANDARD MICROCIRCUIT DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A	CHECKED BY Tim H. Noh																
	APPROVED BY Monica L. Poelking	MICROCIRCUIT, DIGITAL, BIPOLAR, ADVANCED SCHOTTKY, TTL, BUFFER, THREE-STATE, MONOLITHIC SILICON															
	DRAWING APPROVAL DATE 92-01-21																
	REVISION LEVEL A	SIZE A	CAGE CODE 67268	5962-90781													
		SHEET		1 OF 12													

1. SCOPE

1.1 Scope. This drawing documents two product assurance class levels consisting of high reliability (device classes Q and M) and space application (device class V). A choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of Radiation Hardness Assurance (RHA) levels are reflected in the PIN.

1.2 PIN. The PIN is as shown in the following example:



1.2.1 RHA designator. Device classes Q and V RHA marked devices meet the MIL-PRF-38535 specified RHA levels and are marked with the appropriate RHA designator. Device class M RHA marked devices meet the MIL-PRF-38535, appendix A specified RHA levels and are marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device type(s). The device type(s) identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	54F125	Quad buffer, 3-state

1.2.3 Device class designator. The device class designator is a single letter identifying the product assurance level as follows:

<u>Device class</u>	<u>Device requirements documentation</u>
M	Vendor self-certification to the requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A
Q or V	Certification and qualification to MIL-PRF-38535

1.2.4 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
C	GDIP1-T14 or CDIP2-T14	14	Dual in-line
D	GDFP1-F14 or CDFP2-F14	14	Flat package
2	CQCC1-N20	20	Square leadless chip carrier

1.2.5 Lead finish. The lead finish is as specified in MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

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1.3 Absolute maximum ratings. 1/

Supply voltage range (V_{CC})	-0.5 V dc to +7.0 V dc
Input voltage range (V_{IN})	-0.5 V dc to +7.0 V dc
Input current range (I_{IN})	-30.0 mA to +5.0 mA
Output applied in output High output state range (V_{OUT})	-0.5 V to V_{CC}
Current applied to output in Low output state (I_{OUT})	96 mA
Storage temperature range (T_{STG})	-65°C to +150°C
Thermal resistance, junction-to-case (Θ_{JC})	See MIL-STD 1835
Junction temperature (T_J)	+175°C
Lead temperature (soldering, 10 seconds)	+300°C
Maximum power dissipation (P_D) 2/	220 mW

1.4 Recommended operating conditions.

Supply voltage (V_{CC})	+4.5 V to +5.5 V dc
Minimum high level input voltage (V_{IH})	2.0 V dc
Maximum low level input voltage (V_{IL})	0.8 V dc
Maximum input clamp current (I_{IK})	-18 mA
Maximum high level output current (I_{OH})	-12 mA
Maximum low level output current (I_{OL})	48 mA
Case operating temperature range (T_C)	-55°C to +125°C

1.5 Digital logic testing for device classes Q and V.

Fault coverage measurement of manufacturing logic tests (MIL-STD-883, test method 5012) XX percent 3/

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

- MIL-STD-883 - Test Method Standard Microcircuits.
- MIL-STD-973 - Configuration Management.
- MIL-STD-1835 - Interface Standard For Microcircuit Case Outlines.

1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.
 2/ Maximum power dissipation is defined as $V_{CC} \times I_{CC}$ and must withstand the added P_D due to the short-circuit output test (e.g., I_{OS}).
 3/ Values will be added when they become available.

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HANDBOOKS

DEPARTMENT OF DEFENSE

- MIL-HDBK-103 - List of Standard Microcircuit Drawings (SMD's).
- MIL-HDBK-780 - Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device classes Q and V shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. The individual item requirements for device class M shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. This drawing has been modified to allow the manufacturer to use the alternate die/fabrication requirements of paragraph A.3.2.2 of MIL-PRF-38535 or other alternative approved by the Qualifying Activity.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein for device classes Q and V or MIL-PRF-38535, appendix A and herein for device class M.

3.2.1 Case outline. The case outline shall be in accordance with 1.2.4 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth table. The truth table shall be as specified on figure 2.

3.2.4 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.5 Test circuit and switching waveforms. The test circuit and switching waveforms shall be as specified on figure 4.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-HDBK-103. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device. For RHA product using this option, the RHA designator shall still be marked. Marking for device classes Q and V shall be in accordance with MIL-PRF-38535. Marking for device class M shall be in accordance with MIL-PRF-38535, appendix A.

3.5.1 Certification/compliance mark. The certification mark for device classes Q and V shall be a "QML" or "Q" as required in MIL-PRF-38535. The compliance mark for device class M shall be a "C" as required in MIL-PRF-38535, appendix A. For class Q product built in accordance with A.3.2.2 of MIL-PRF-38535, or as modified in the manufacturer's Quality Management (QM) Plan, the "QD" certification mark shall be used in place of the "QML" or "Q" certification mark.

3.6 Certificate of compliance. For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.6.1 herein). For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6.2 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device classes Q and V, the requirements of MIL-PRF-38535 and herein or for device class M, the requirements of MIL-PRF-38535, appendix A and herein.

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3.7 Certificate of conformance. A certificate of conformance as required for device classes Q and V in MIL-PRF-38535 or for device class M in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DSCC-VA of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change as defined in MIL-STD-973.

3.9 Verification and review for device class M. For device class M, DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.10 Microcircuit group assignment for device class M. Device class M devices covered by this drawing shall be in microcircuit group number 9 (see MIL-PRF-38535, appendix A).

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified		Group A subgroups	Limits		Unit
					Min	Max	
High level output voltage	V _{OH}	V _{CC} = 4.5 V V _{IL} = 0.8 V V _{IH} = 2.0 V	I _{OH} = -3 mA	1, 2, 3	2.4		V
			I _{OH} = -12 mA	1, 2, 3	2.0		
Low level output voltage	V _{OL}	V _{CC} = 4.5 V, V _{IL} = 0.8 V,	I _{OL} = 48 mA V _{IH} = 2.0 V	1, 2, 3		0.5	
Input clamp voltage	V _{IK}	V _{CC} = 4.5 V,	I _{IN} = -18 mA	1, 2, 3		-1.2	
High level input current	I _{IH1}	V _{CC} = 5.5 V,	V _{IN} = 2.7 V	1, 2, 3		20	μA
Input current at maximum input voltage	I _{IH2}	V _{CC} = 0.0 V,	V _{IN} = 7.0 V	1, 2, 3		100	
Low level input current	I _{IL}	V _{CC} = 5.5 V,	V _{IN} = 0.5 V	1, 2, 3		-20	
Off-state output current, High level voltage applied	I _{OZH}	V _{CC} = 5.5 V, V _{OUT} = 2.7 V	V _{IH} = 2.0 V	1, 2, 3		50	
Off-state output current, Low level voltage applied	I _{OZL}	V _{CC} = 5.5 V, V _{OUT} = 0.5 V	V _{IH} = 2.0 V	1, 2, 3		-50	
Short circuit output current <u>1/</u>	I _{OS}	V _{CC} = 5.5 V,	V _{OUT} = 0.0 V	1, 2, 3	-100	-225	mA
Supply current (total) <u>2/</u>	I _{CCH}	V _{CC} = 5.5 V	\overline{nC} = GND nA = 4.5 V	1, 2, 3		24	
	I _{CCL}		\overline{nC} = GND nA = GND	1, 2, 3		40	
	I _{CCZ}		\overline{nC} = 4.5 V nA = 4.5 V	1, 2, 3		35	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics. – Continued.

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Functional tests		See 4.4.1b V _{CC} = 4.5 V, 5.5 V	7, 8A, 8B			
Propagation delay time, nA to nY, low to high	t _{PLH}	C _L = 50 pF R _L = 500 Ω See figure 4	V _{CC} = 5.0 V	9	2.0	6.0
			V _{CC} = 4.5 V and 5.5 V	10, 11	2.0	7.0
Propagation delay time, nA to nY, high to low	t _{PHL}		V _{CC} = 5.0 V	9	3.0	7.5
			V _{CC} = 4.5 V and 5.5 V	10, 11	3.0	8.5
Output enable time to high level	t _{PZH}		V _{CC} = 5.0 V	9	3.5	7.5
			V _{CC} = 4.5 V and 5.5 V	10, 11	3.5	9.0
Output enable time to low level	t _{PZL}		V _{CC} = 5.0 V	9	4.0	8.0
			V _{CC} = 4.5 V and 5.5 V	10, 11	4.0	9.5
Output disable time from high level	t _{PHZ}		V _{CC} = 5.0 V	9	1.5	5.0
			V _{CC} = 4.5 V and 5.5 V	10, 11	1.5	6.5
Output disable time from low level	t _{PLZ}	V _{CC} = 5.0 V	9	1.5	5.5	
		V _{CC} = 4.5 V and 5.5 V	10, 11	1.5	7.5	

1/ Not more than one output should be shorted at a time, and the duration of the short-circuit condition should not exceed one second.

2/ I_{CC} is measured with output open.

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Device type	01	
Case outlines	C and D	2
Terminal number	Terminal symbol	
1	$\overline{1C}$	NC
2	1A	$\overline{1C}$
3	1Y	1A
4	$\overline{2C}$	1Y
5	2A	NC
6	2Y	$\overline{2C}$
7	GND	NC
8	3Y	2A
9	3A	2Y
10	$\overline{3C}$	GND
11	4Y	NC
12	4A	3Y
13	$\overline{4C}$	3A
14	V _{CC}	$\overline{3C}$
15	----	NC
16	----	4Y
17	----	NC
18	----	4A
19	----	$\overline{4C}$
20	----	V _{CC}

NC = No connection

FIGURE 1. Terminal connections.

Inputs		Outputs
\overline{nC}	nA	nY
L	L	L
L	H	H
H	X	Z

H = High voltage level
 L = Low voltage level
 X = Don't care
 Z = High impedance

FIGURE 2. Truth table.

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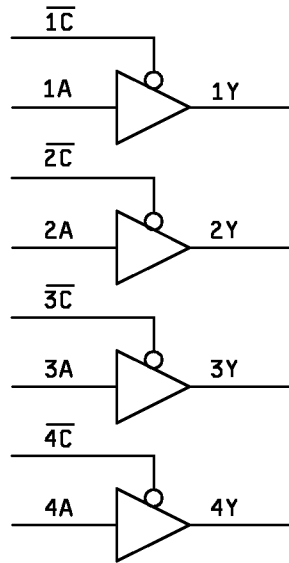
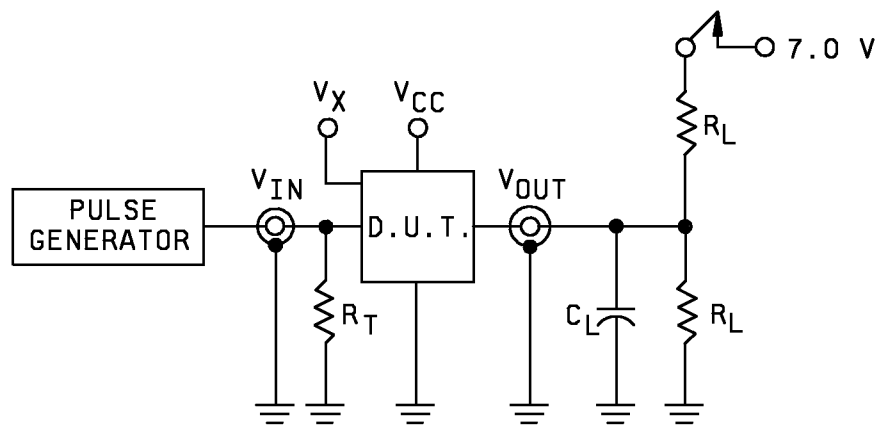


FIGURE 3. Logic diagram.



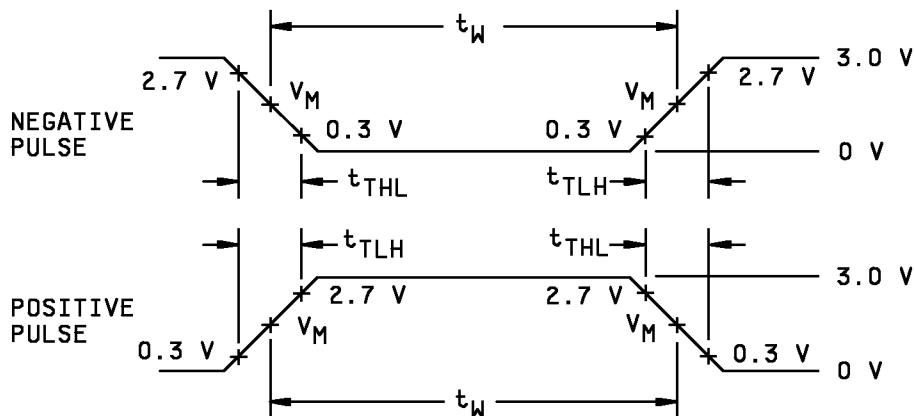
Test	Switch
t_{PLZ}	Closed
t_{PZL}	Closed
All other	Open

NOTES:

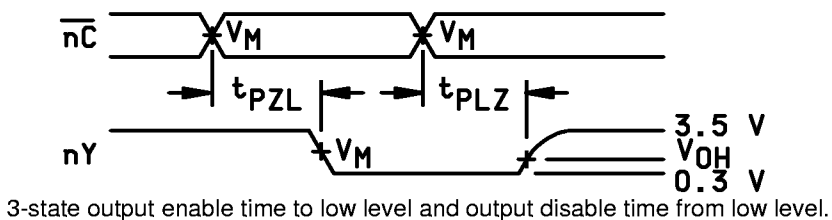
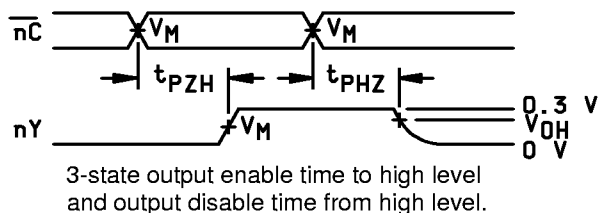
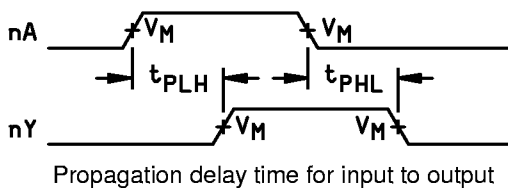
1. R_L = Load resistor, see table I for value.
2. C_L = Load capacitance includes jig and probe capacitance. See table I for value.
3. R_T = Termination resistance should be equal to Z_{OUT} of the pulse generator.
4. V_X = Unlocked pins must be held at 0.8 V, ≥ 2.7 V, or open per truth table.

FIGURE 4. Test circuit and switching waveforms.

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Input Pulse Characteristics			
Rep. rate	Pulse width	t_{TLH}	t_{THL}
1 MHz	500 ns	≤ 2.5 ns	≤ 2.5 ns



NOTE: For all waveforms, $V_M = 1.5$ V.

FIGURE 4. Test circuit and switching waveforms - Continued.

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4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. For device class M, sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. For device classes Q and V, screening shall be in accordance with MIL-PRF-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection.

4.2.1 Additional criteria for device class M.

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015.
 - (2) $T_A = +125^\circ\text{C}$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein.

4.2.2 Additional criteria for device classes Q and V.

- a. The burn-in test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document revision level control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II herein.
- c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in MIL-PRF-38535, appendix B.

4.3 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-PRF-38535. Inspections to be performed shall be those specified in MIL-PRF-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4 Conformance inspection. Technology conformance inspection for classes Q and V shall be in accordance with MIL-PRF-38535 including groups A, B, C, D, and E inspections and as specified herein except where option 2 of MIL-PRF-38535 permits alternate in-line control testing. Quality conformance inspection for device class M shall be in accordance with MIL-PRF-38535, appendix A and as specified herein. Inspections to be performed for device class M shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. For device class M, subgroups 7, 8A and 8B tests shall be sufficient to verify the truth table. For device classes Q and V, subgroups 7, 8A and 8B shall include verifying the functionality of the device; these tests shall have been fault graded in accordance with MIL-STD-883, test method 5012 (see 1.5 herein).

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TABLE II. Electrical test requirements.

Test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)	Subgroups (in accordance with MIL-PRF-38535, table III)	
	Device class M	Device class Q	Device class V
Interim electrical parameters (see 4.2)			1, 7
Final electrical parameters (see 4.2)	1/ 1, 2, 3, 7, 8A, 8B, 9, 10, 11	1/ 1, 2, 3, 7, 8A, 8B, 9, 10, 11	2/ 1, 2, 3, 7, 8A, 8B, 9, 10, 11
Group A test requirements (see 4.4)	1, 2, 3, 7, 8A, 8B, 9, 10, 11	1, 2, 3, 7, 8A, 8B, 9, 10, 11	1, 2, 3, 7, 8A, 8B, 9, 10, 11
Group C end-point electrical parameters (see 4.4)	1, 2, 3	1, 2, 3, 7, 8A, 8B, 9, 10, 11	1, 2, 3, 7, 8A, 8B, 9, 10, 11
Group D end-point electrical parameters (see 4.4)	1, 2, 3	1, 2, 3, 7, 8A, 8B, 9, 10, 11	1, 2, 3, 7, 8A, 8B, 9, 10, 11
Group E end-point electrical parameters (see 4.4)	1, 7, 9	1, 7, 9	1, 7, 9

- 1/ PDA applies to subgroup 1.
- 2/ PDA applies to subgroups 1 and 7.

4.4.2 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table II herein.

4.4.2.1 Additional criteria for device class M. Steady-state life test conditions, method 1005 of MIL-STD-883:

- a. Test condition A, B, C or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
- b. $T_A = +125^\circ\text{C}$, minimum.
- c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.4.2.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The test circuit shall be maintained under document revision level control by the device manufacturer's TRB in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

4.4.3 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table II herein.

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4.4.4 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein).

- a. End-point electrical parameters shall be as specified in table II herein.
- b. For device classes Q and V, the devices or test vehicle shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535 for the RHA level being tested. For device class M, the devices shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535, appendix A for the RHA level being tested. All device classes must meet the postirradiation end-point electrical parameter limits as defined in table I at $T_A = +25^\circ\text{C} \pm 5^\circ\text{C}$, after exposure, to the subgroups specified in table II herein.
- c. When specified in the purchase order or contract, a copy of the RHA delta limits shall be supplied.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor prepared specification or drawing.

6.1.2 Substitutability. Device class Q devices will replace device class M devices.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-973 using DD Form 1692, Engineering Change Proposal.

6.3 Record of users. Military and industrial users should inform Defense Supply Center Columbus when a system application requires configuration control and which SMD's are applicable to that system. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0525.

6.4 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43216-5000, or telephone (614) 692-0674.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535 and MIL-HDBK-1331.

6.6 Sources of supply.

6.6.1 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in QML-38535. The vendors listed in QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DSCC-VA and have agreed to this drawing.

6.6.2 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-90781
		REVISION LEVEL A	SHEET 12

STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 99-10-22

Approved sources of supply for SMD 5962-90781 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-9078101MCA	0C7V7	54F125/MCA
5962-9078101MDX	<u>3/</u>	54F125BDX
5962-9078101M2X	<u>3/</u>	54F125B2X

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- 2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from an approved source.

Vendor CAGE
number

0C7V7

Vendor name
and address

QP Labs
3605 Kifer Road
Santa Clara, CA 95051

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.